## Amendments to the Claims

This listing of claims will replace all prior versions, and listings, of claims in the application:
Listing of Claims:

 (Original) A hemifumarate crystal of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°.

## Claim 2. (Cancelled)

3. (Currently Amended) A hemifumarate X-hydrate of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°.

4. (Currently Amended) A process for preparing a hemifumarate X—hydrate of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, said process comprising the step of treating conditioning a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, to obtain said hemifumarate X-hydrate.

- 5 **-**

5. (Currently Amended) A process for preparing a hemifumarate anhydrate of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, said process comprising the step of treating drying under reduced pressure a hemifumarate crystal form of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, to obtain said hydrate.

6. (Currently Amended) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

- 6 -

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) 6.6° and 8.5°, to obtain said hydrate.

7. (Currently Amended) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising the step of treating—conditioning a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, wherein said hemifumarate anhydrate is obtained by treating—drying under reduced pressure a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°.

8. (Original) A hemifumarate crystal of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $5.4^{\circ}$ ,  $10.4^{\circ}$ ,  $10.7^{\circ}$  and  $12.1^{\circ}$ .

9. (Original) A hemifumarate crystal of a compound of formula (I):

containing acetone and showing strong X-ray diffraction peaks at diffraction angles 2 theta =  $5.4^{\circ}$ ,  $10.4^{\circ}$ ,  $10.7^{\circ}$  and  $12.1^{\circ}$  measured by X-ray diffractometry using Cu-K $\alpha$  radiation.

10. (Currently Amended) A hemifumarate crystal of a compound of formula (I):

containing methylethylketone and showing strong X-ray diffraction peaks at diffraction angles 2 theta =  $5.4^{\circ}$ ,  $10.4^{\circ}$ ,  $10.7^{\circ}$  and  $12.1^{\circ}$  measured by X-ray diffractometry using Cu-K $\alpha$  radiation.

11. (Original) A hemifumarate crystal of a compound of formula (I):

containing tetrahydrofuran and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4°, 10.4°,

10.7° and 12.1° measured by X-ray diffractometry using Cu-K $\alpha$  radiation.

Claims 12-15. (Cancelled)

16. (Currently Amended) A process for preparing a hemifumarate anhydrate of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, said process comprising the step of obtaining said anhydrate by treating drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.

17. (Currently Amended) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of showing strong X-ray diffraction peaks at diffraction angles  $2\theta = 7.1^{\circ}$  and  $14.2^{\circ}$ , said process comprising the step of obtaining said hydrate by treating drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.

18. (Currently Amended) A process for preparing a hemifumarate X—hydrate of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising the step of treating conditioning a hemifumarate anhydrate of

the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, wherein said anhydrate is obtained by treating drying under reduced pressure a hemifumarate crystal of Claim 8, 9, 10 or 11.